

HQ:NSC19/No Al

Soft Tapping Mode and LFM AFM Probe

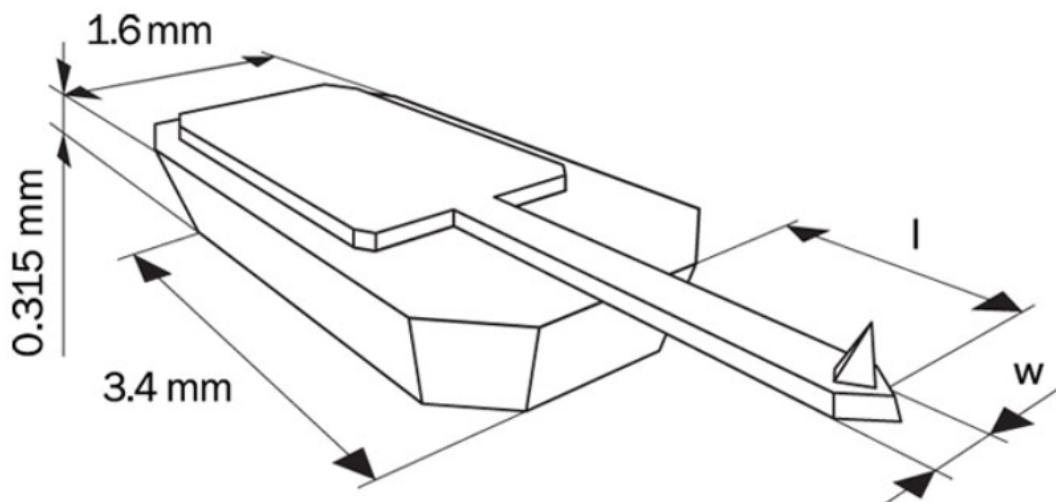
AFM probes of the HQ:NSC19 series combine relatively high resonance frequency and low force constant, which makes them suitable for imaging soft and fragile surfaces at relatively high speeds in Soft tapping mode. They are **compatible with Bruker ScanAsyst® PeakForce Tapping™***. These AFM probes are also used in Lateral force microscopy due to their high sensitivity to lateral forces.

The HQ AFM probes offer high consistency of the AFM tip radius, the AFM cantilever reflectivity and the quality factor.

** ScanAsyst® and PeakForce Tapping™ are trademarks of Bruker Corporation*

Coating

none



AFM Probe Specifications

AFM Tip

SHAPE	HEIGHT	FULL CONE ANGLE	RADIUS
Rotated	15 μm (12 – 18 μm)*	40°	< 8 nm

AFM Cantilever

CANTILEVER	SHAPE	FORCE CONST.	RES. FREQ.	LENGTH	WIDTH	THICKNESS
Cantilever A	Beam	0.5 N/m (0.05 – 2.3 N/m)*	65 kHz (25 – 120 kHz)*	125 μm (1 – 130 μm)*	22.5 μm (19.5 – 25.5 μm)*	1 μm (0.5 – 1.5 μm)*

* typical values